

OptiMOS[™]-5 Power Transistor





Features

- OptiMOS™ power MOSFET for automotive applications
- N-channel Enhancement mode Normal Level
- MSL1 up to 260°C peak reflow
- 175 °C operating temperature
- Green product (RoHS compliant)
- 100% Avalanche tested

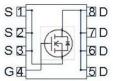
Product Summary

V_{DS}	80	V
R _{DS(on),max}	10.2	mΩ
I _D	50	Α

PG-TDSON-8-33



Туре	Package	Marking
IAUC50N08S5N102	PG-TDSON-8-33	5N08102



Maximum ratings, at T_i =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Drain current	ID	V _{GS} =10 V, Chip limitation ^{1,2)}	50	А
		V _{GS} =10V, DC current	50	
		T_a =85 °C, V_{GS} =10 V, R _{thJA} on 2s2p ^{2,3)}	12	
Pulsed drain current ²⁾	I _{D,pulse}	T _C =25 °C	200	
Avalanche energy, single pulse ²⁾	E _{AS}	I _D =29 A	45	mJ
Avalanche current, single pulse	IAS	-	29	А
Gate source voltage	V _{GS}	-	±20	V
Power dissipation	P _{tot}	T _C =25 °C	60	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$	-	-55 +175	°C



Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	
Thermal characteristics ²⁾						
Thermal resistance, junction - case	R _{thJC}	-	-	-	2.5	K/W
Thermal resistance, junction - ambient ⁴⁾	R _{thJA}	-	-	24.9	-	

Electrical characteristics, at $T_{\rm j}$ =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0V, I _D =1mA	80	-	-	V
Gate threshold voltage	V _{GS(th)}	$V_{\rm DS}=V_{\rm GS}, I_{\rm D}=24~\mu{\rm A}$	2.2	3.0	3.8	
Zero gate voltage drain current	I _{DSS}	V _{DS} =80V, V _{GS} =0V, T _j =25°C	-	0.1	1	μA
		$V_{\rm DS}$ =80V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =85°C ²⁾	-	1	20	
Gate-source leakage current	I _{GSS}	V _{GS} =20V, V _{DS} =0V	-	-	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =6V, I _D =12.5A	-	12.3	15.8	mΩ
		V _{GS} =10V, I _D =25A	-	8.4	10.2	
Gate resistance ²⁾	R _G	-	-	1.1	-	Ω



Parameter	Symbol	Symbol Conditions	Values			Unit
			min.	typ.	max.	
Dynamic characteristics ²⁾						
Input capacitance	C iss		_	1072	1394	pF
Output capacitance	C oss	V _{GS} =0V, V _{DS} =40V, f=1MHz	-	204	265	
Reverse transfer capacitance	C _{rss}		-	13	20	
Turn-on delay time	t _{d(on)}		-	4	-	ns
Turn-off delay time	t _{d(off)}	V _{DD} =40V, V _{GS} =10V,	-	6	-	1
Rise time	t _r	$I_{\rm D}$ =25A, $R_{\rm G,ext}$ =3.5 Ω	-	2	-	
Fall time	t _f	1	-	4	-	1
Gate Charge Characteristics ²⁾		T	Ι	1	Π	1
Gate to source charge	Q _{gs}		-	5	7	nC
Gate to drain charge	Q _{gd}	$V_{\rm DD}$ =40V, $I_{\rm D}$ =25A, $V_{\rm GS}$ =0 to 10V	-	4	6	
Gate charge total	Q _g		-	16	21	
Gate plateau voltage	V _{plateau}		-	5.0	-	V
Reverse Diode						
Diode continous forward current ²⁾	Is	T _C =25°C	-	-	50	А
Diode pulse current ²⁾	I _{S,pulse}	T _C =25 °C	-	-	200	
Diode forward voltage	V _{SD}	V _{GS} =0V, I _F =25 A, T _j =25°C	-	0.9	1.2	V
Reverse recovery time ²⁾	t _{rr}	V _R =40V, I _F =50A,	-	32	-	ns
Reverse recovery charge ²⁾	Q _{rr}	$di_F/dt = 100A/\mu s$	-	25	-	nC

¹⁾ Practically the current is limited by the overall system design including the customer-specific PCB.

 $^{^{2)}\,\}mbox{The parameter}$ is not subject to production test - verified by design/characterization.

³⁾ Device on a four-layer 2s2p FR4 PCB defined in accordance with JEDEC standards (JESD51-5-7). PCB is vertical in still air.

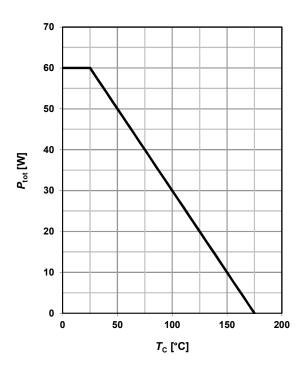


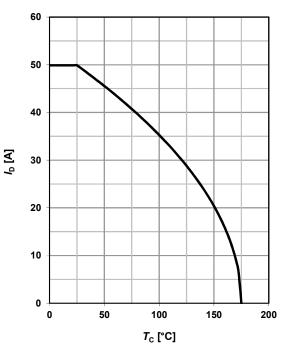
1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} = 10 \text{ V}$$

2 Drain current

$$I_D = f(T_C); V_{GS} = 10 \text{ V}$$





3 Safe operating area

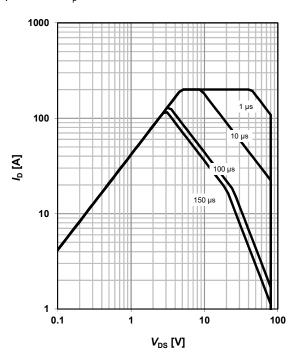
$$I_D = f(V_{DS}); T_C = 25 \text{ °C}; D = 0$$

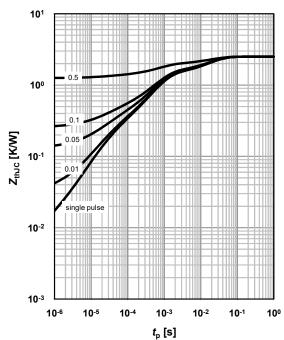
parameter: $t_{\rm p}$

4 Max. transient thermal impedance

$$Z_{\text{thJC}} = f(t_p)$$

parameter: $D = t_p/T$







5 Typ. output characteristics

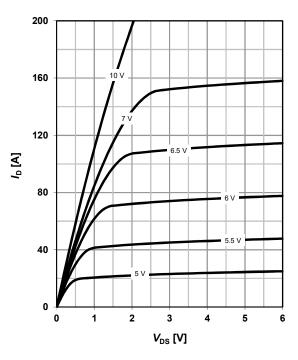
 $I_D = f(V_{DS}); T_j = 25 °C$

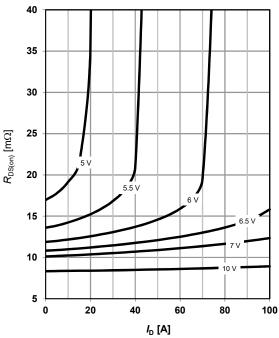
parameter: V_{GS}

6 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(I_D); T_j = 25 \text{ °C}$

parameter: V_{GS}





7 Typ. transfer characteristics

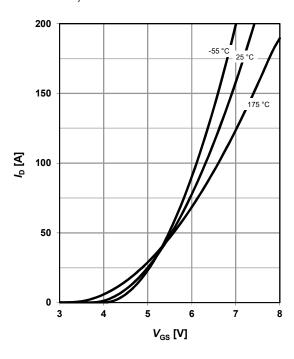
 $I_D = f(V_{GS}); V_{DS} = 6V$

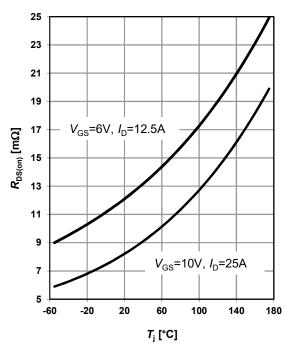
parameter: $T_{\rm j}$

8 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(T_i);$

parameter: I_{D,} V_{GS}







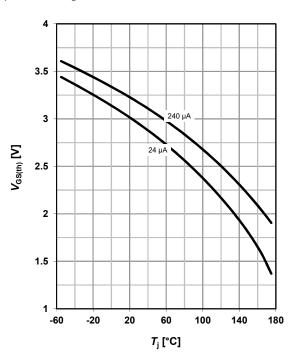
9 Typ. gate threshold voltage

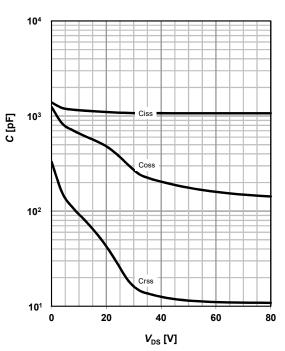
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: I_D

10 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$





11 Typical forward diode characteristics

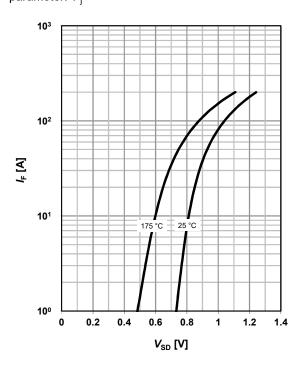
 $I_F = f(V_{SD})$

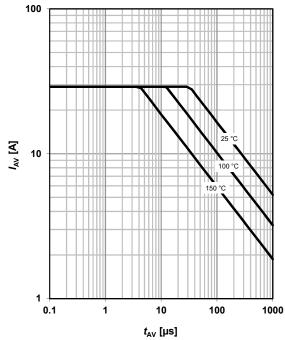
parameter: $T_{\rm j}$

12 Avalanche characteristics

 $I_{AS} = f(t_{AV})$

parameter: T_{j(start)}







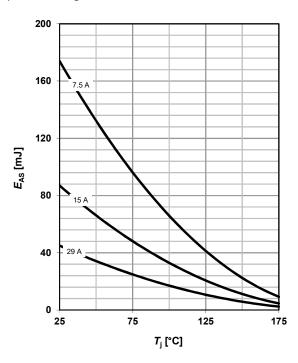
13 Avalanche energy

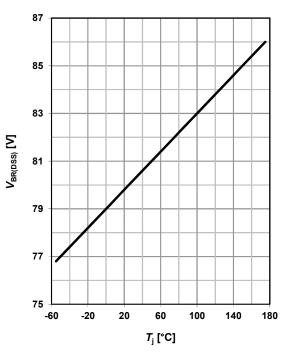
 $E_{AS} = f(T_j)$

parameter: I_D

14 Drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_j); I_D = 1 \text{ mA}$$

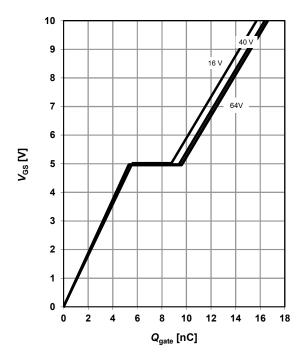




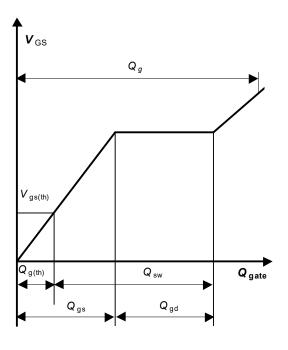
15 Typ. gate charge

 $V_{GS} = f(Q_{gate}); I_D = 25 A pulsed$

parameter: $V_{\rm DD}$

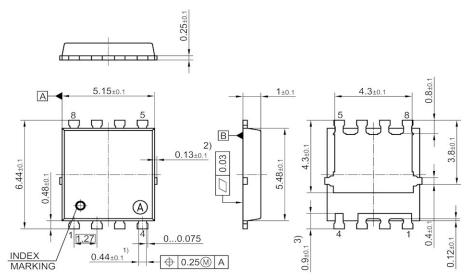


16 Gate charge waveforms



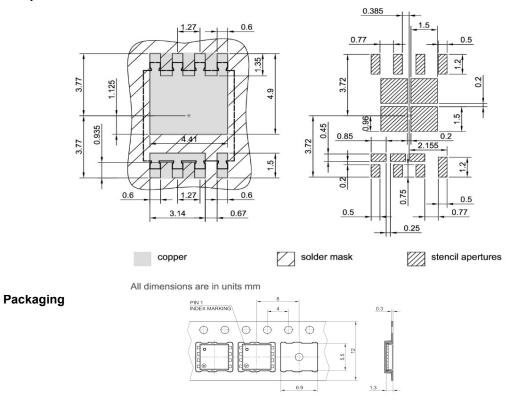


Package Outline



1) EXCLUDE MOLD FLASH
2) REMOVAL ON MOLD GATE, INTRUSION 0.1MM AND PROTRUSION 0.1MM
3) LEAD LENGTH UP TO ANTI FLASH LINE
4)ALL METAL SURFACE ARE PLATED, EXCEPT AREA OF CUT
ALL DIMENSIONS ARE IN UNITS MM
THE DRAWING IS IN COMPLIANCE WITH ISO 128 & PROJECTION METHOD 1 [

Footprint



ALL DIMENSIONS ARE IN UNITS MM THE DRAWING IS IN COMPLIANCE WITH ISO 128 & PROJECTION METHOD 1 [\iff]



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Revision History

Version	Date	Changes
Revision 1.0	2021-05-14	Final Data Sheet
Revision 1.1	2021-06-18	Datasheet file name updated